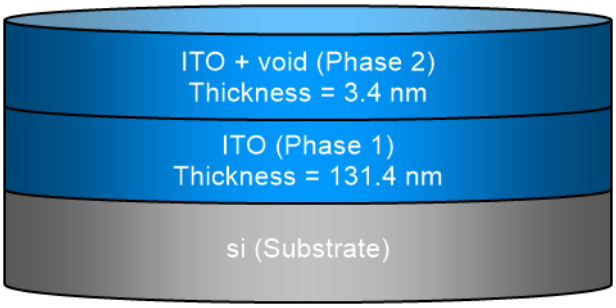
SEA regression report summary

Sample ID
001d 70° 2

Details	
Software and regression log	
Software about	Semilab - Spectroscopic Ellipsometry Analyzer - SEA
Software version	1.7.1
Officially licensed to	MIT
Operator	operator
Date and time of regression	14-07-2021 13:56
Comments	

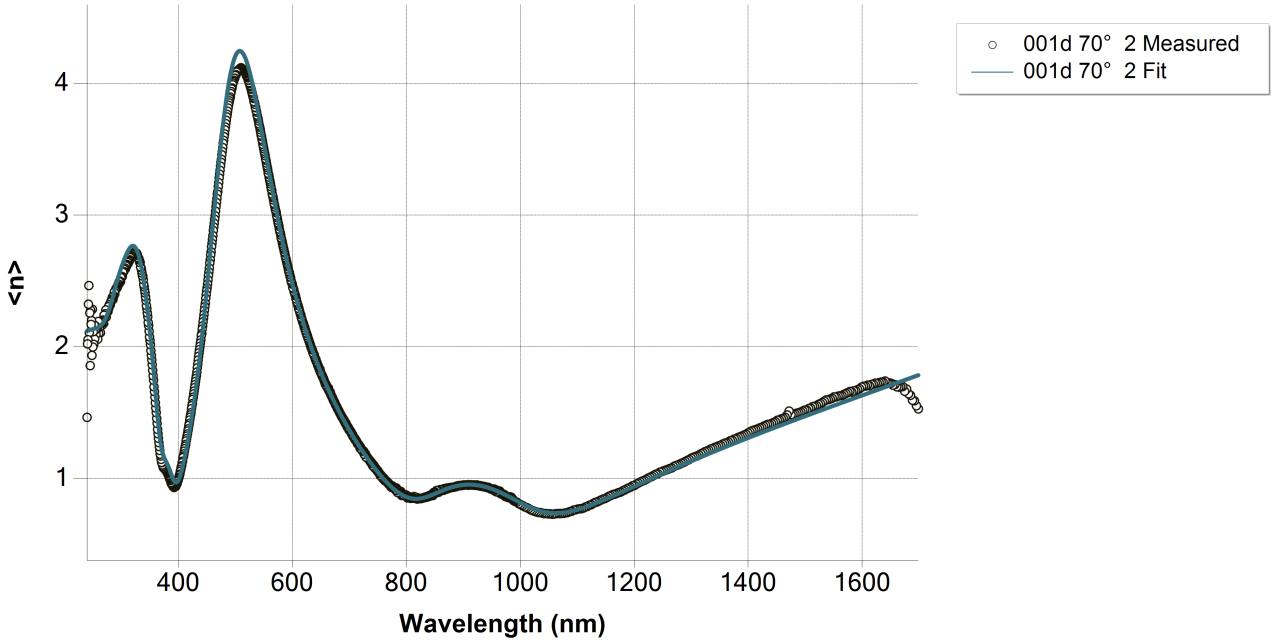
Layer structure	
Overview	
	
Optical model	
Phase 2	ITO + void
Diffusion	
Phase 1	ITO
Dispersion law	Tauc-Lorentz
	Drude

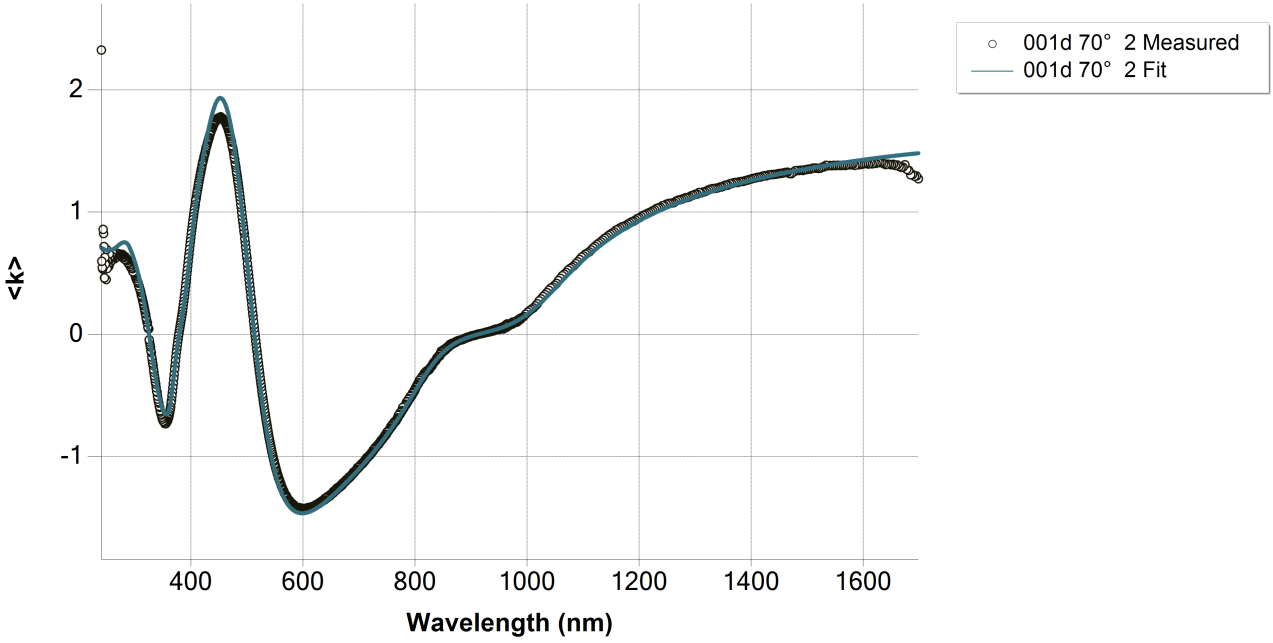
Regression results

Measurement information				
Measurement file path	C:\Users\emmabat\ito-si\001d.smdx			
Angle of Incidence	70°			
Regression details				
Regression 1 (EllipsoReflectance)				
Wavelength range	239.84 - 1698.83 nm			
Angle of Incidence	70°			
Fit to	<n>, <k>			
Angular Aperture	0°			
Fit algorithm	LMA			
Results				
Parameters	Value	Fitted	2 σ confidence limit	Unit
Model				
AOI Shift	0			°
Angular Aperture	0			°
Phase 2 (ITO + void)				
Thickness	3.354	X	0.19046	nm
Depolarization coefficient	0.33333			
Concentration 1	0.5			
Concentration 2	0.5			
Phase 1 (ITO)				
Thickness	131.389	X	0.29223	nm
A (eV)	467.79138	X	146.19743	eV
E0 (eV)	7.00561	X	1.43502	eV
C (eV)	49.99977	X	6.63001	eV
Eg (eV)	2.73982	X	0.016529	eV
E_p (eV)	0.86075	X	0.012327	eV
E_Γ (eV)	0			eV
Eps_inf	0			
Derived parameters	Value			
Phase 2 (ITO + void)				
n @ 632.8 nm	1.499			
k @ 632.8 nm	0			
Phase 1 (ITO)				
n @ 632.8 nm	2.0557			
k @ 632.8 nm	0			
Substrate (si)				
n @ 632.8 nm	3.8811			
k @ 632.8 nm	0.0195			
Drude derived parameters	Value			Unit
Phase 1 (ITO)				
Conductivity (S/m)	∞ ± NaN			S/m
Resistivity (mΩ.cm)	0 ± NaN			mΩ.cm
Resistance (Ω/sq)	0 ± NaN			Ω/sq
N type dopant concentration (at/cm3)	1.3433E+20 ± 3.8476E+18			at/cm3

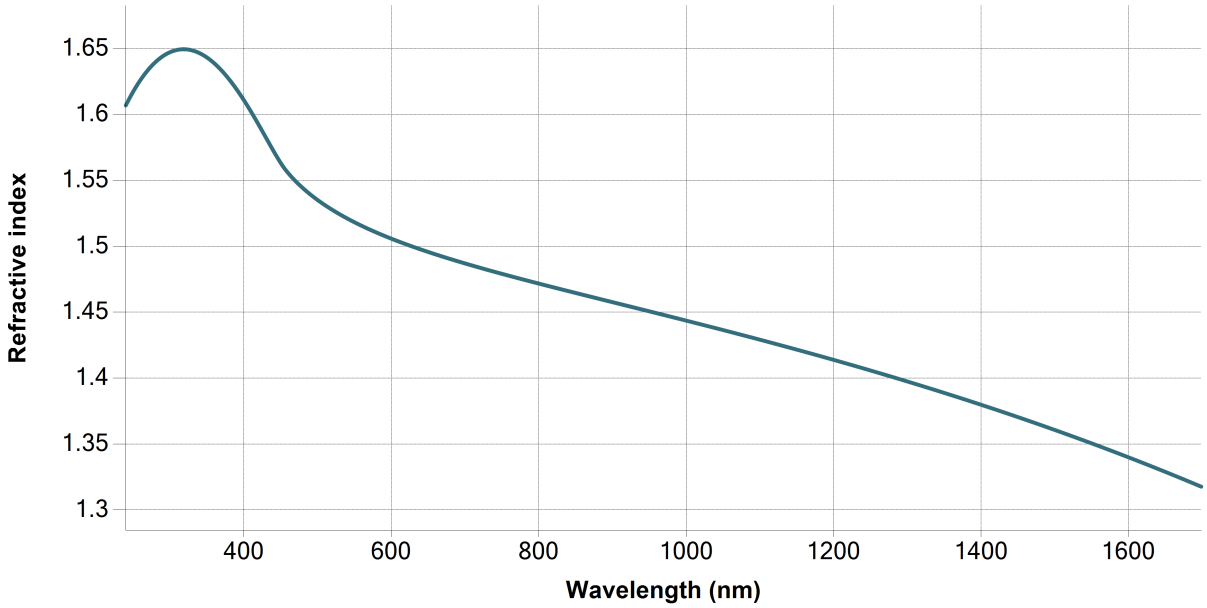
P type dopant concentration (at/cm3)	1.9881E+20 ± 5.6944E+18	at/cm3
N type dopant mobility (cm2/Vs)	∞ ± NaN	cm2/Vs
P type dopant mobility (cm2/Vs)	∞ ± NaN	cm2/Vs
Fit quality		
R^2	0.99569	
RMSE	0.06154	

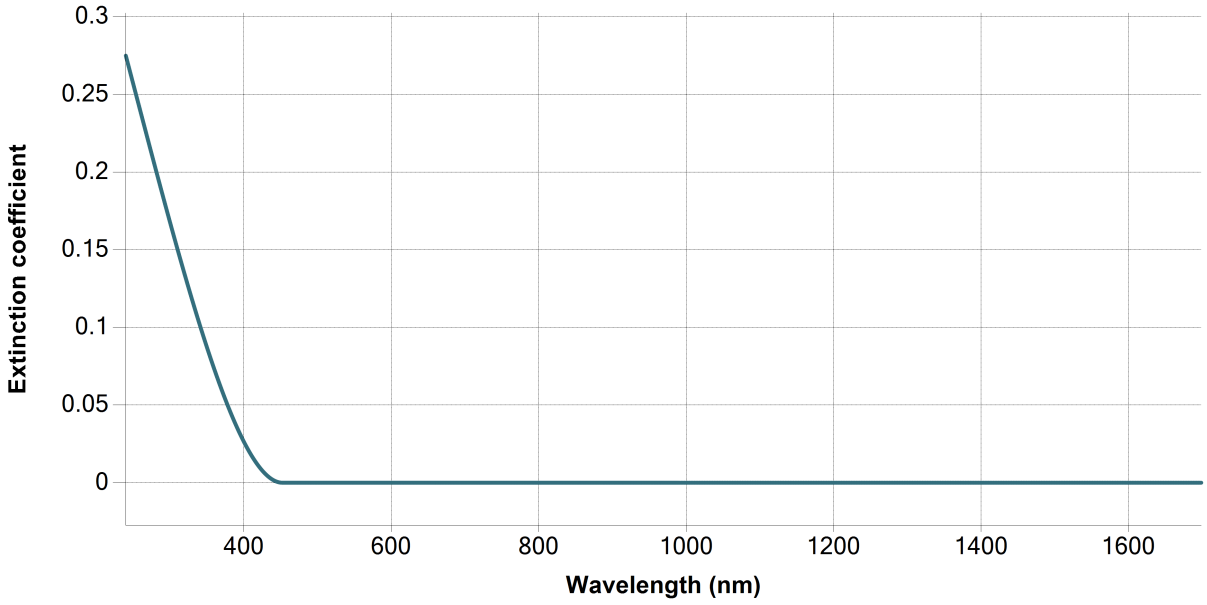
Regression graphs



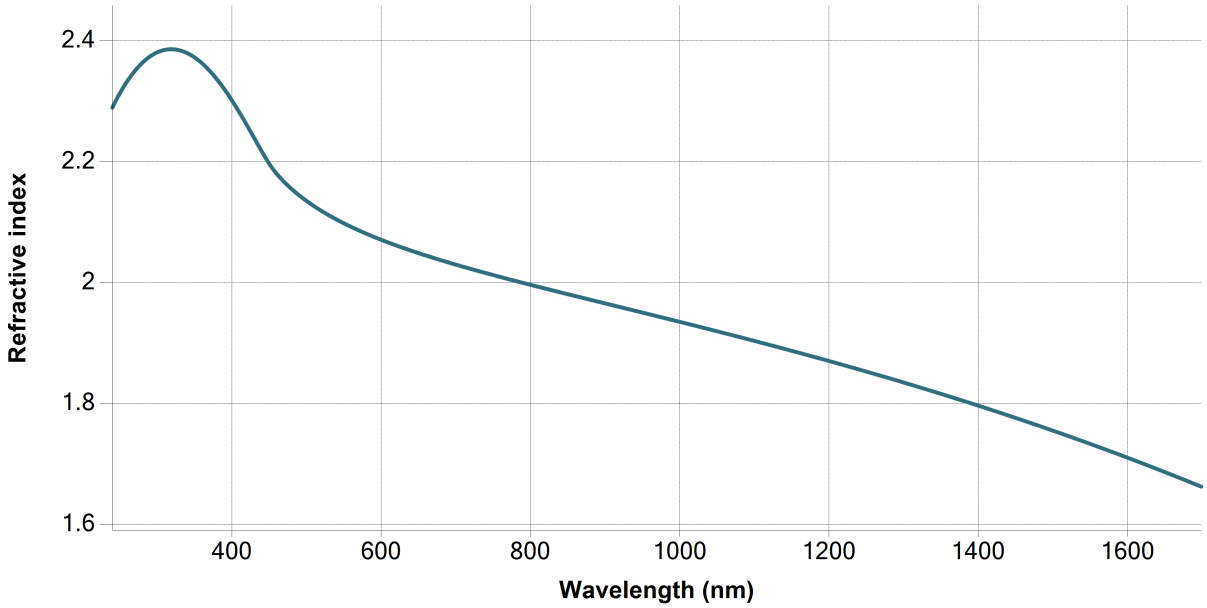


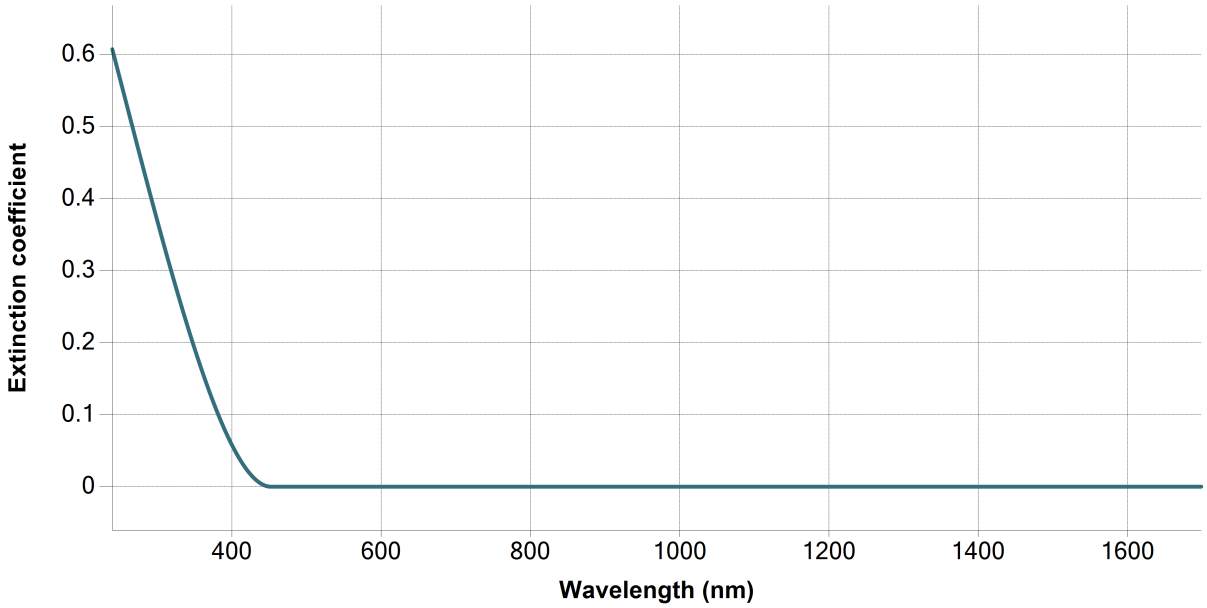
Phase 2 (ITO + void) - Dispersion graphs



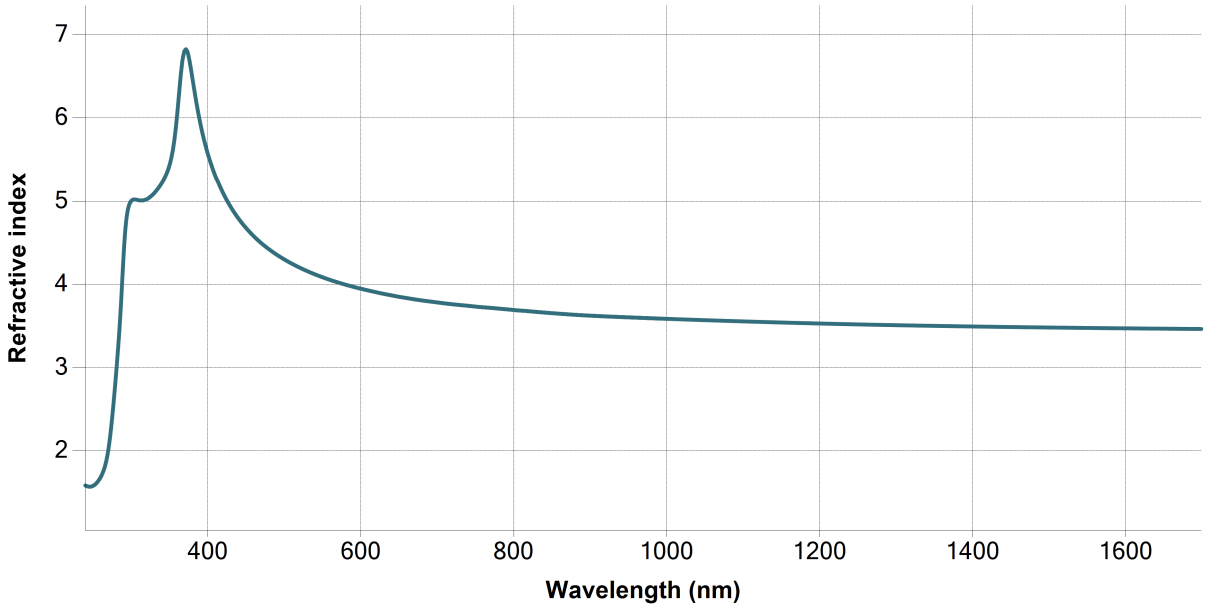


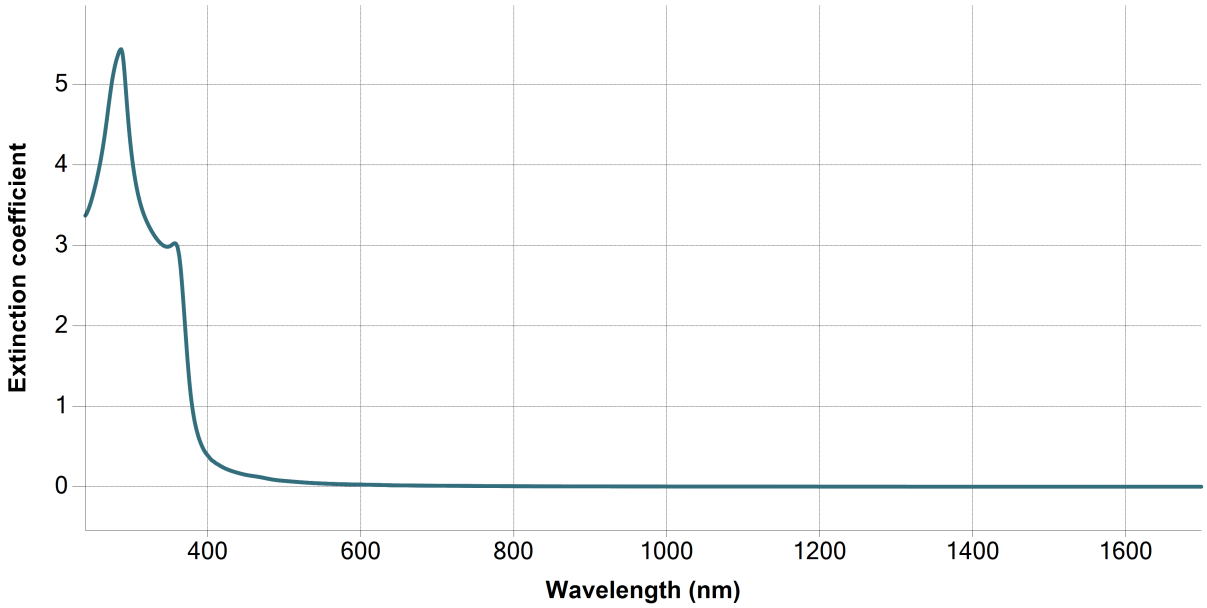
Phase 1 (ITO) - Dispersion graphs





Substrate (si) - Dispersion graphs





Correlation coefficients							
	Ph2 - ITO + void - Thickness	Ph1 - ITO - Thickness	Ph1 - Tauc-Lorentz[1] - A (eV)	Ph1 - Tauc-Lorentz[1] - E0 (eV)	Ph1 - Tauc-Lorentz[1] - C (eV)	Ph1 - Tauc-Lorentz[1] - Eg (eV)	Ph1 - Drude[2] - E_p (eV)
Ph2 - ITO + void - Thickness	1	-0.4797	-0.1437	0.1398	-0.1425	-0.0529	-0.0944
Ph1 - ITO - Thickness		1	0.0315	-0.0332	0.0504	0.0168	-0.2831
Ph1 - Tauc-Lorentz[1] - A (eV)			1	-0.9812	0.9277	0.9102	0.4005
Ph1 - Tauc-Lorentz[1] - E0 (eV)				1	-0.8385	-0.9436	-0.312
Ph1 - Tauc-Lorentz[1] - C (eV)					1	0.7391	0.5091
Ph1 - Tauc-Lorentz[1] - Eg (eV)						1	0.2969
Ph1 - Drude[2] - E_p (eV)							1